

Lithium Diffusion and Surface Oxidation on Battery Materials at Room Temperature Characterized by AES and LEED

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Introduction

Next-generation clean energy storage needs high-quality materials, interfaces, and stabilizing compounds to enhance the performance of the existing Li-based technology.

There is also strong interest in new materials that will accumulate more Li atoms in the crystalline structure with high Li ion mobility, stable charge cycling and log life.

Existing Li ion based technology is a proved successful but still is bearing low energy density, capacity degradation and dendrite growth.

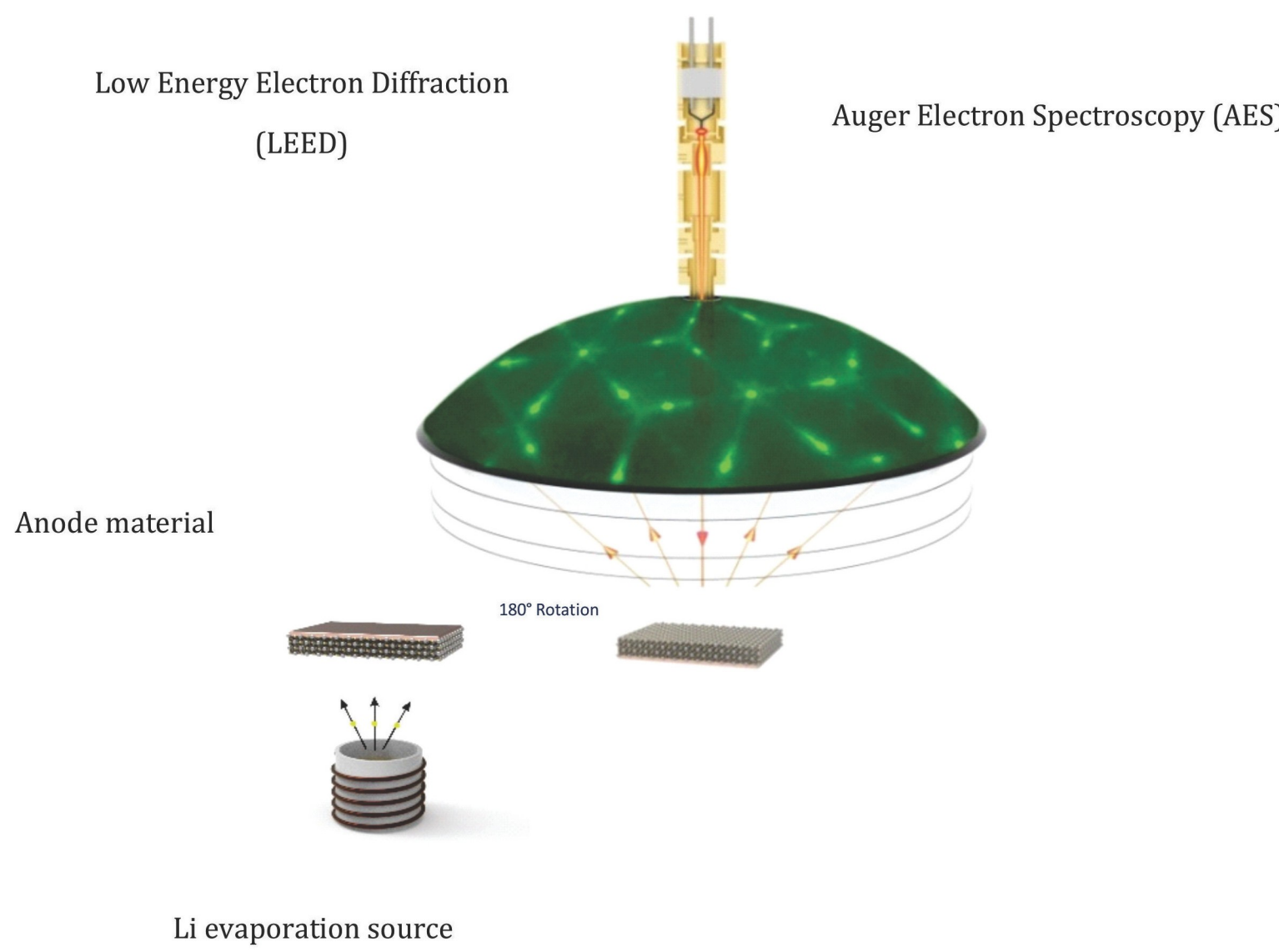
Those factors require a wider spectrum of advanced tools for the battery materials characterization and our method is addressing that field.

Li transport properties are the key factor for the battery's performance.

Li passive diffusion is defined as the process of Li atoms/ions migration under a concentration gradient and activated by thermal energy from atomic vibrations of the host structure.

This process of passive Li diffusion is strongly correspond to the active Li diffusion processes where external energy component such electrical potential is applied. It is expected that materials that exhibit good Li passive diffusion will perform much better under the external electrical potential.

Experimental Set-up



Sample preparation and characterisation:

- Single crystal is cleaned by thermal annealing after loading to UHV system

- Thin film of Li is evaporated under UHV conditions

- Surface crystallography with LEED

- Measurements of Li peak at 52 eV with AES and other peaks depending on the substrate composition

- Li deposition thickness is monitored with Quarts Crystal Microbalance

Results - Li Diffusion

Substrate and Comments	LEED Clean	LEED 5Å Lithium	AES Spectrum (Before/After Evaporation)
HOPG (Graphite) Strong Li diffusion, no change to surface crystalline structure (25°C)			
Si(111) No Li diffusion, drastic change to surface crystalline structure (25°C)			
SiC6H Some Li diffusion, small effect on surface crystalline structure (25°C)			

Substrate and Comments	LEED - Clean	LEED - 5Å Lithium	AES (After Evaporation)
Diamond (100) CVD (25°C) Li diffusion, no change			Small Li peak detected: 4 mV
Si (100) (25°C) no Li diffusion, change			Large Li peak: 70 mV
Si (211) (25°C) no Li diffusion, change			Large Li peak: 66 mV
LiNbO ₃ - Mg Doped (25°C) Li diffusion, some change			No Li peak detected

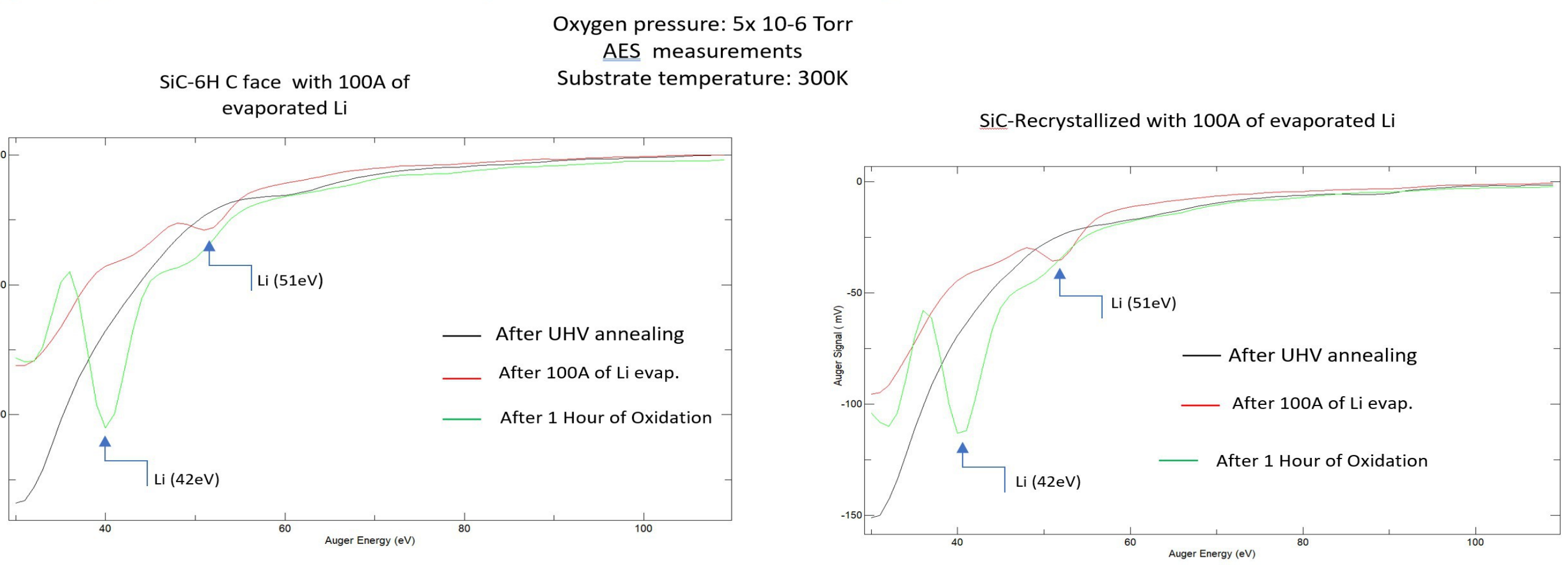
Results - Li Oxidation

Comparison of AES data for SiC single crystal and polycrystalline samples
All experiments at Room Temperature

Process	SiC6H	Si face	SiC CVD Si present on surface
After UV cleaning	Si92eV: 32.5 mV		Si92eV: 20 mV
After 100 A of Li evaporation	Si92eV: 0 mV Li51 eV: 70 mV		Si92eV: 0 mV Li51 eV: 25.8 mV
Process	SiC6H	C face	SiC Recrystallized, very low Si present on the surface
After UV cleaning	Si92eV: 0 mV		Si92eV: spectrum is "bent"
After 100 A of Li evaporation	Si92eV: 0 mV Li51 eV: 4 mV		Si92eV: 0 mV Li51 eV: 6.6 mV

The presence of Si atoms on the surface limits Li diffusion into bulk
Li diffusion into a single crystal structure is more preferential than diffusion into grain boundaries
Substrate temperature: 300K

Oxygen exposure of SiC with an evaporated dose of Li -100 Angstrom



Li Auger peak is 19 times larger after oxidation, and energy is shifted to 42 eV Substrate during oxidation temperature: 300K

Li Auger peak is 8 times larger after oxidation, and energy is shifted to 42 eV Substrate during oxidation temperature: 300K

Discussion

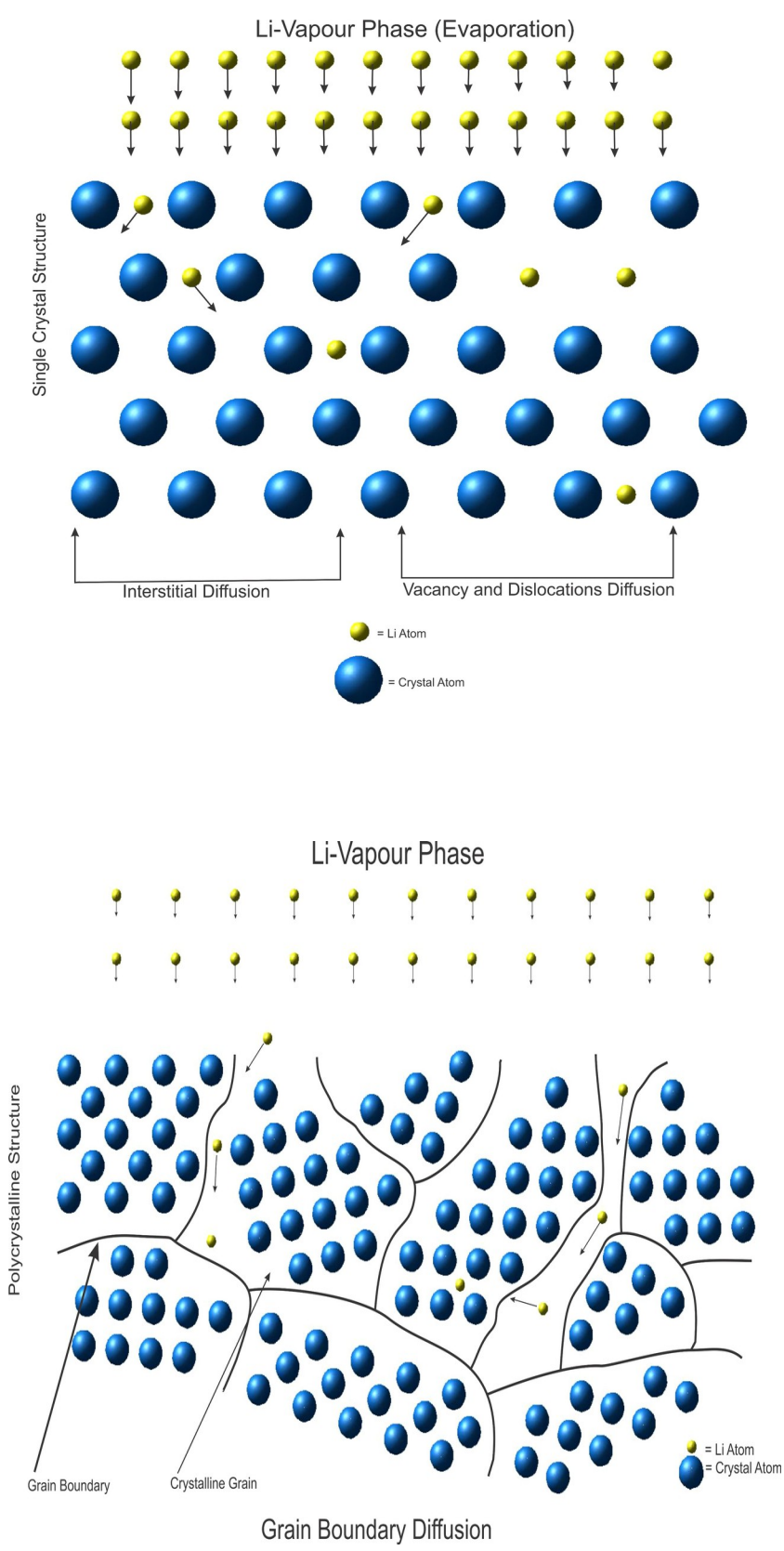
Classification of the tested materials

We identified 3 categories of characterized materials:

	"Rapid lattice diffusion": Materials with passive rapid Li diffusion in lattice structure: HOPG and no effect on the long-range structural order
	"No lattice diffusion": Materials with no passive Li diffusion and a strong effect on long-range structural order – polycrystallization or amorphization Si(100), Si(211), SrTiO ₂ , Ga ₂ O ₃ Silicon requires a nano-engineering process to create the Li diffusion path
	"Moderate lattice diffusion": Materials that have moderate passive Li diffusion and some effect on the long-range structural order SiC, CVD Diamond, SiO ₂ /Si(001), LiNbO ₃ , TiO ₂ , TiO ₂ /Si(111), CdS, InP

This approach offers a unique method to measure transport of Li atoms/ions into the solid structure and simplify the understanding of diffusion processes especially if the single-crystal structures are used. The single structures are free from grain boundaries. This approach allows for classification of the materials that are attractive to Lithium diffusion based on the pure lattice component.

The conditions which limit Li diffusion such as lithium oxidation, lithium plating and the role of grain boundaries can be investigated selectively and independently of other factors.



Conclusions

- There is a large group of materials with moderate Li diffusion at room temperature: SiC, SiO₂/Si(001), Diamond CVD, LiNbO₃, TiO₂, CdS and InP.

- These materials can be used as a thin film interface at the electrode-electrolyte interface of Li-based batteries reducing plating, dendrite growth or capacity degradation

- Silicon lattice is presenting the barrier for Li diffusion. Silicon is very attractive material because of its high capacity for bonding with Li. However, the lack of lattice diffusion require to develop special nano-structural paths allowing migration of Li ions.

- Ga₂O₃ is the case that possibly unsaturated oxygen atoms on the surface are "trapping" Li atoms. Layered structure of Ga₂O₃ is not helping with that.

- SiC demonstrate the case that Li lattice diffusion is more preferential than grain boundary diffusion

- Li oxidation reaction on the surface is more preferential than Li diffusion Li atoms are diffusing from bulk to surface to get oxidized
- Oxidation reaction on Lithiated single crystal is 2 times faster than on Lithiated polycrystalline SiC